

Notice of References Cited

Application/Control No.

10/032,035

Applicant(s)/Patent Under
Reexamination
OHNISHI ET AL.

Examiner

Ted Kim

Art Unit

3746

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,279,127	01-1994	Napoli, Phillip D.	60/754
	B	US-6,530,221	03-2003	Sattinger et al.	60/725
	C	US-4,199,936	04-1980	Cowan et al.	60/725
	D	US-5,417,056	05-1995	Johnson et al.	60/725
	E	US-3,974,647	08-1976	Lewis et al.	60/725
	F	US-6,351,947	03-2002	Keller et al.	60/725
	G	US-5,590,531	01-1997	Desaulty et al.	60/752
	H	US-6,041,590	03-2000	Hayton et al.	60/766
	I	US-2,610,467	09-1952	Name not available	60/800
	J	US-4,422,300	12-1983	Dierberger et al.	60/757
	K	US-5,758,504	06-1998	Abreu et al.	60/754
	L	US-4,833,881	05-1989	Vdoviak et al.	60/725
	M	US-5,644,918	07-1997	Gulati et al.	60/725

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP0576717A1	03-1992	EP	ABB	na
	O	JP 7-293276	07-1995	JP	Mitsubishi	na
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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